

<b>Notice of References Cited</b>	Application/Control No. 10/031,461	Applicant(s)/Patent Under Reexamination CHIBA ET AL.	
	Examiner Yelena G. Gakh, Ph.D.	Art Unit 1743	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 10142144 A	05-1998	Japan	NISHINAKA et al.	G01N 21/27
	O	JP 53095695A	08-1978	Japan	KYOTO	G01N 21/02
	P	JP 10142143 A	05-1998	Japan	TSUGE et al.	G01N 21/27
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.